

Test Report

Applicant:	Yongkang ShiYa Aluminum Factory
Product Name:	Scooter
Brand Name:	N/A
Model No.:	ES-03
Date of Receipt : Date of Test: Date of Report:	Jan.26, 2018 Jan.29-31, 2018 Feb.02, 2018
Prepared by:	Shenzhen Most Technology Service Co., Ltd.

The EMC testing has been performed on the submitted samples and found in compliance with the council EMC directive 2014/30/EU.

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TEST REPORT DECLARATION

Report Number	MTE/AVJ/E18010261						
	Yongkang ShiYa	Yongkang ShiYa Aluminum Factory					
Applicant	169#,FengXiang Road,GuShan Industrial zone,YongKang City,Zhejiang						
	Yongkang ShiYa	Aluminum Factory					
Manufacturer	169#,FengXiang	Road, GuShan Industrial zone, YongKang City, Zhejiang					
	Product Name	Scooter					
Product	Model No.	ES-03					
	Power Supply	DC 5V by USB port DC 3.7V by battery					
Test Result	The EUT was for	and compliant with the requirement(s) of the standards.					
Standard	EN 61000-6-3:2007+A1:2011, EN 61000-3-2:2014, EN 61000-3-3:2017, EN 61000-6-1:2007(IEC 61000-4-2:2008, IEC 61000-4-3: 2006+A1:2007+A2:2010, IEC 61000-4-4:2012, IEC 61000-4-5:2014, IEC 61000-4-6:2013, IEC 61000-4-8:2009, IEC 61000-4-11:2004)						
maximum emis and its performa configurations r Co., Ltd. Is assu shows that the F This report app							
in the revision of	of the document.	Bra jiang					
Prepared by		Ava jiang					
Reviewed by	Sunmy						
		Sunny deng					
Approved by		Jutter					
		Yvette Zhou(Manager)					



1. GENERAL INFORMATION

1.1. Description of Device (EUT)

Description	:	Scooter
Model Number	:	ES-03, ES-01, ES-02, ES-03, ES-04, ES-05
Remark	:	Used ES-03 does all tests

1.2. Operational Mode(s) of EUT

Order Number	:	Test Mode(s)
1	:	Running

1.3. Test Voltage(s) of EUT

Order Number	:	Test Voltage(s)
1	:	DC 5V by USB port
		DC 3.7V by battery



2. DESCRIPTION OF TEST STANDARD

The intention of this publication is to establish uniform requirements for the radio disturbance level of the equipment contained in the scope, to fix limits of disturbance, to describe methods of measurement and to standardize operating conditions and interpretation of results.

The following referenced standard are indispensable for the application of this report.

Referenced Description below:

EN 61000-6-3:2007+A1:2011 Electromagnetic compatibility (EMC) -- Part 6-3: Generic standards - Emission standard for residential, commercial and light-industrial environments.

EN 61000-3-2:2014 Limits for harmonic current emissions (equipment input current <= 16 A per phase).

EN 61000-3-3:2017

Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current <= 16 A per phase and not subject to conditional connection.

EN 61000-6-1:2007

Electromagnetic compatibility (EMC) -- Part 6-1: Generic standards - Immunity for residential, commercial and light-industrial environments



3. LABORATORY INFORMATION

3.1. Laboratory Name

Shenzhen Most Technology Service Co., Ltd.

3.2. Location

No.5, 2nd Langshan Road, North District, Hi-tech Industrial Park, Nanshan, Shenzhen, Guangdong, China

3.3. Test facility

3m Anechoic Chamber	:	Nov. 28, 2012 File on Federal Communication Commission Registration Number:490827
Shielding Room	:	Nov. 28, 2012 File on Federal Communication Commission Registration Number:490827
EMC Lab.	:	Accredited by TUV Rheinland Shenzhen Audit Report: UA 50149851 Mar. 12, 2009
		Accredited by Industry Canada Registration Number: 7103A-1 Oct. 22, 2012
		Accredited by TIMCO Registration Number: Q1460 March 28, 2010

3.4. Measurement Uncertainty

No.	Item	Uncertainty
1.	Uncertainty for Conducted Disturbance Test	1.25dB
2.	Uncertainty for Radiated Disturbance Test	3.15dB



4. SUMMARY OF TEST RESULTS

Test Item	Standard	Limits	Results
Conducted disturbance at mains terminals	EN 61000-6-3:2007+ A1:2011		PASS
Radiated disturbance	EN 61000-6-3:2007+ A1:2011		PASS
Harmonic current emissions	EN 61000-3-2:2014	Class A	N/A
Voltage fluctuations & flicker	EN 61000-3-3:2017		PASS
IMM	UNITY (EN 61000-6-1:20	07)	
Test Item	Basic Standard	Performance Criteria	Results
Electrostatic discharge (ESD)	IEC 61000-4-2:2008	В	PASS
Radio-frequency, Continuous radiated disturbance	IEC 61000-4-3:2006 +A1:2007+A2:2010	А	PASS
Electrical fast transient (EFT)	IEC 61000-4-4:2012	В	PASS
Surge (Input a.c. power ports)	IEC (1000 4 5 0014	В	PASS
Surge (Telecommunication ports)	IEC 61000-4-5:2014	В	N/A
Radio-frequency, Continuous conducted disturbance	IEC 61000-4-6:2013	А	PASS
Power frequency magnetic field	IEC 61000-4-8:2009	Α	PASS
Voltage dips, 0% reduction		В	PASS
	IEC 61000-4-11:2004	С	PASS
Voltage dips, 30% reduction			PASS



5. BLOCK DIAGRAM OF TEST SETUP

The equipments are installed test to meet EN61000-6-3 requirement and operating in a manner which tends to maximize its emission characteristics in a normal application. EUT was tested in normal configuration (Please See following Block diagrams)

5.1. Block Diagram of connection between EUT and simulation-EMI

Test Mode: Running



(EUT: Scooter)

5.2. Block Diagram of connection between EUT and simulation-EMS

Test Mode: Running



(EUT: Scooter)



6. TEST INSTRUMENT USED

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal.
						Interval
1.	Test Receiver	Rohde & Schwarz	ESCI	100492	Mar. 10, 17	1 Year
2.	L.I.S.N.	Rohde & Schwarz	ENV216	100093	Mar. 10, 17	1 Year
3.	Coaxial Switch	Anritsu Corp	MP59B	6200283933	Mar. 07, 17	1 Year
4.	Terminator	Hubersuhner	50Ω	No.1	Mar. 07, 17	1 Year
5.	RF Cable	SchwarzBeck	N/A	No.1	Mar. 07, 17	1 Year

6.1. For Conducted Disturbance at Mains Terminals Emission Test

6.2. For Radiation Test (In Anechoic Chamber)

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal.
						Interval
	Test Receiver	Rohde & Schwarz	ESCI	101202	Mar. 10, 17	1 Year
	Bilog Antenna	Sunol	JB3	A121206	Mar. 14, 17	1 Year
	Cable	Resenberger	N/A	NO.1	Mar. 07, 17	1 Year
	Cable	SchwarzBeck	N/A	NO.2	Mar. 07, 17	1 Year
	Cable	SchwarzBeck	N/A	NO.3	Mar. 07, 17	1 Year
	DC Power Filter	DuoJi	$DL2 \times 30B$	N/A	N/A	N/A
	Single Phase Power	DuoJi	FNF 202B30	N/A	N/A	N/A
	Line Filter					
	3 Phase Power Line	DuoJi	FNF 402B30	N/A	N/A	N/A
	Filter					

6.3. For Harmonic / Flicker Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal.
						Interval
	AC Power Source	Kikusui	AC40MA	LM003232	Mar. 10, 17	1 Year
	Test Analyzer	Kikusui	KHA1000	LM003720	Mar. 10, 17	1 Year
	Line Impendence	Kikusui	LIN40MA-	LM002352	Mar. 10, 17	1 Year
	Network		PCR-L			

6.4. For Electrostatic Discharge Immunity Test

Item	Equipment	Manufacturer	Model No.	Serial No.		Cal. Interval
1.	ESD Tester	Kikusui	KES4021	LM003537	Mar. 10, 17	1 Year



Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal.
						Interval
1.	Signal Generator	IFR	2032	203002/100	Mar. 14, 17	1 Year
2.	Amplifier	A&R	150W1000	301584	NCR	NCR
3.	Dual Directional Coupler	A&R	DC6080	301508	Mar. 14, 17	1 Year
4.	Power Sensor	A&R	PH2000	301193	Mar. 14, 17	1 Year
5.	Power Meter	A&R	PM2002	302799	Mar. 14, 17	1 Year
6.	Field Monitor	A&R	FM5004	300329	Mar. 14, 17	1 Year
7.	Field Probe	A&R	FP5000	300221	Mar. 14, 17	1 Year
8.	Log-periodic Antenna	A&R	AT1080	16512	Mar. 14, 17	1 Year
9.	RF Cable	MIYAZAKI	N/A	No.1/No.2	Mar. 07, 17	1 Year

6.5. For RF Strength Susceptibility Test

6.6. For Electrical Fast Transient/Burst Immunity Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal.
						Interval
1.	EMCPRO System	EM Test	UCS-500-M4	V0648102026	Mar. 10, 17	1 Year

6.7. For Surge Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal.
						Interval
1.	EMCPRO System	EM Test	UCS-500-M4	V0648102026	Mar. 10, 17	1 Year

6.8. For Injected Currents Susceptibility Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal.
						Interval
1.	Signal Generator	IFR	2032	203002/100	Mar. 10, 17	1 Year
2.	Amplifier	A&R	150W1000	301584	NCR	NCR
3.	CDN	FCC	FCC-801-M2-25	47	Mar. 10, 17	1 Year
4.	CDN	FCC	FCC-801-M3-25	107	Mar. 10, 17	1 Year
5.	EM Injection Clamp	FCC	F-203I-23mm	403	Mar. 10, 17	1 Year
6.	RF Cable	MIYAZAKI	N/A	No.1/No.2	Mar. 07, 17	1 Year

6.9. For Magnetic Field Immunity Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Cal. Interval
1.	EMCPRO System	EM Test	UCS-500-M4	V0648102026	

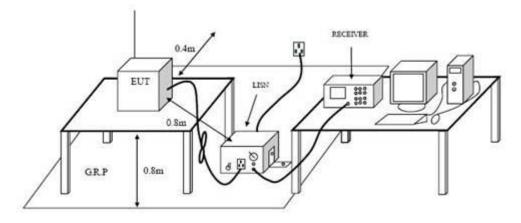
6.10. For Voltage Dips and Interruptions Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal.
						Interval
1.	EMCPRO System	EM Test	UCS-500-M4	V0648102026	Mar. 10, 17	1 Year



7. CONDUCTED DISTURBANCE AT MAINS TERMINALS TEST

7.1. Configuration of Test System



7.2. Test Standard

EN 61000-6-3:2007+A1:2011

7.3. Power Line Conducted Disturbance at Mains Terminals Limit

	Maximum R	F Line Voltage
Frequency	Quasi-Peak Level	Average Level
	dB(µV)	dB(µV)
150kHz ~ 500kHz	66 ~ 56*	56 ~ 46*
500kHz ~ 5MHz	56	46
5MHz ~ 30MHz	60	50

Notes: 1. * Decreasing linearly with logarithm of frequency.

2. The lower limit shall apply at the transition frequencies.

7.4. Test Procedure

The EUT was placed on a non-metallic table, 80cm above the ground plane. The EUT Power connected to the power mains through a line impedance stabilization network (L.I.S.N. 1#). This provided a 50-ohm coupling impedance for the EUT (Please refer to the block diagram of the test setup and photographs). The other peripheral devices power cord connected to the power mains through a line impedance stabilization network (L.I.S.N.#2). Both sides of power line were checked for maximum conducted interference. In order to find the maximum emission, the relative positions of equipments and all of the interface cables were changed according to EN 61000-6-3 on conducted Disturbance test.

The bandwidth of test receiver is set at 9kHz.

The frequency range from 150kHz to 30MHz is checked. The test result are reported on Section 7.5.



7.5. Conducted Disturbance at Mains Terminals Test Results

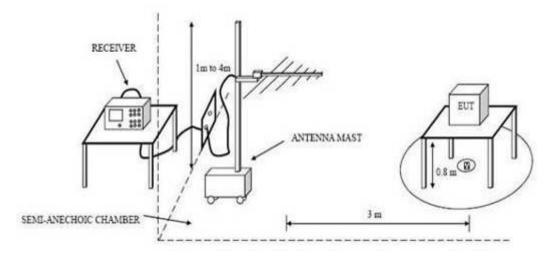
7.5.1. Test Results: **PASS**

- 7.5.2. If the average limit is met when using a quasi-peak detector, the EUT shall be deemed to meet both limits and measurement with average detector is unnecessary.
- 7.5.3. Emission Level= Correct Factor + Reading Level.
- 7.5.4. The test data and the scanning waveform are attached within Appendix I.



8. RADIATED DISTURBANCE TEST

8.1. Configuration of Test System



8.2. Test Standard

EN 61000-6-3:2007+A1:2011

8.3. Radiated Disturbance Limit

All emanations from devices or system, including any network of conductors and apparatus connected thereto, shall not exceed the level of field strengths specified below:

FREQUENCY	DISTANCE	FIELD STRENGTHS LIMITS
(MHz)	(Meters)	(dBµV/m)
30 ~ 230	3	40
230 ~ 1000	3	47

Note: 1. The lower limit shall apply at the transition frequencies.

2. Distance refers to the distance in meters between the test antenna and the closed point of any part of the EUT.

8.4. Test Procedure

The EUT was placed on a non-metallic table, 80 cm above the ground plane inside a semi-anechoic chamber. An antenna was located 3m from the EUT on an adjustable mast. A pre-scan was first performed in order to find prominent radiated emissions. For final emissions measurements at each frequency of interest, the EUT were rotated and the antenna height was varied between 1m and 4m in order to maximize the emission. Measurements in both horizontal and vertical polarities were made and the data was recorded. In order to find the maximum emission, the relative positions of equipments and all of the interface cables were changed according to EN 61000-6-3 on Radiated Disturbance test.

The bandwidth setting on the test receiver is 120 kHz.

The frequency range from 30MHz to 1000MHz is checked. The test result are reported on Section 8.5.



8.5. Radiated Disturbance Test Results

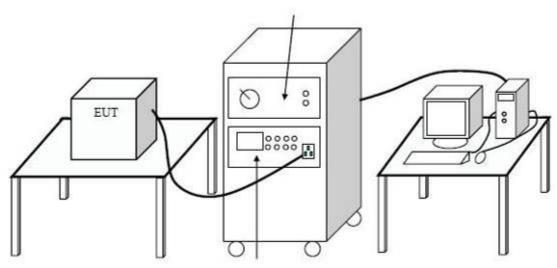
- 8.5.1.Test Results: PASS
- 8.5.2.Emission Level= Correct Factor + Reading Level.
- 8.5.3.All reading are Quasi-Peak values.
- 8.5.4. The test data and the scanning waveform are attached within Appendix II.



9. HARMONIC CURRENT TEST

9.1. Configuration of Test System

HARMONIC & FLICKER ANALYSER



9.2. Test Standard

EN 61000-3-2:2014; Class A

9.3. Test Limits

For Class A equipment, the hamonics of the input current shall not exceed the values given in below:

Harmonic order	Maximum permissible
n	Harmonic current
	А
Odd ha	rmonics
3	2.30
5	1.14
7	0.77
9	0.40
11	0.33
13	0.21
$15 \leq n \leq 39$	0.15 15/n
Even ha	rmonics
2	1.08
4	0.43
6	0.30
$8 \leq n \leq 40$	0.23 8/n

9.4. Test Results

9.4.1.Test Results: N/A



10. VOLTAGE FLUCTUATIONS & FLICKER TEST

10.1.Configuration of Test System

Same as Section 9.1.

10.2.Test Standard

EN 61000-3-3:2017

10.3.Test Limits

The limits shall be applicable to voltage fluctuations and flicker at the supply terminal s of the equipment under test, the following limites apply:

the value of Pst shall not be greater than 1.0;

the value of Plt shall not be greater than 0.65;

the value of d(t) during a voltage change shall not exceed 3.3% for more than 500ms; the relative steady-state voltage change, dc, shall not exceed 3.3%;

the maximum relative voltage change dmax, shall not exceed

a) 4% without additional conditions;

b) 6% for equipment which is:

Switched manually, or

Swithced automatically more frequently than twice per day, and also has either a delayed restart(the delay being not less than a few thens of seconds), or manual restart, after a power supply interruption.

c) 7% for equipment which is

Attended whilst in use (for example: hair dryers, vacuum cleaners, kitchen equipment such as mixers, garden equipment such as lawn mowers, portable tools such as electric drills), or

switched on automatically, or is intended to be switched on manually, no more than twice per day, and also has either a delayed restart(the delay being not less than a few tens of seconds) or manual restart, after a power supply interruption.

10.4.Test Results

10.4.1.Test Results: PASS

10.4.2.All test data on the following pages.



Voltage Fluctuation and Flicker TEST REPORT

Company	PC Partner	Test Engineer	LPH
Model name Type	ZOTAC AMP BOX ZT-TB3BOX-BB		
Serial No.		Type of test	EN61000-3-3:2013 *IEC61000-3-3:2013
Operating mode Date of test Climatic condition	Running PC System+ping 2018/1/30 14:23:38 T:26:H:53%		EN61000-4-15:2011 *IEC61000-4-15:2010
Memo	1.20,1.0070	Power analyzer Supply Source Reference Impedance	KHA1000,Ver1.50 AC 230V/50HZ

Test Data of Voltage Fluction and Flicker

FINAL TEST RESULT	PASS
Nominal Voltage	230V
Nominal Frequency	50Hz
Plt Test duration	600s
Flicker Margin	100%
d Measurement Margin	100%

	Pst	dc(%)	dmax(%)	d(t)>3.3%(ms)	Judge
Limit	1.000	3.300	4.000	500	
Seg. 1	0.010	0.004	0.035	0	Pass
Seg. 2	3,000	a, sea			
Seg. 3					
Seg. 4			-,		
Seg. 5			-,		
Seg. 6		-,		(access)	
Seg. 7	a,				
Seg. 8	2,000				
Seg. 9					
Seg.10	-,		-,		
Seg.11		12,222	-,	1000000	
Seg.12	a	s	1,000		

	Plt	Judge
Limit	0.650	-
Measurement	0.004	Pass



11.IMMUNITY PERFORMANCE CRITERIA

The test results shall be classified in terms of the loss of function or degradation of performance of the equipment under test, relative to a performance level by its manufacturer or the requestor of the test, or the agreed between the manufacturer and the purchaser of the product.

Criterion A:

The apparatus shall continue to operate as intended during and after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacture, when the apparatus is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level of the permissible performance loss is not specified by the manufacturer, either of these may be derived from the product description and documentation and what the user may reasonably expect from the apparatus if used as intended.

Criterion B:

The apparatus shall continue to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacture, when the apparatus is used as intended. The performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed. No change of actual operating state or stored data is allowed. If the minimum performance level of the permissible performance loss is not specified by the manufacturer, either of these may be derived from the product description and documentation and what the user may reasonably expect from the apparatus if used as intended.

Criterion C:

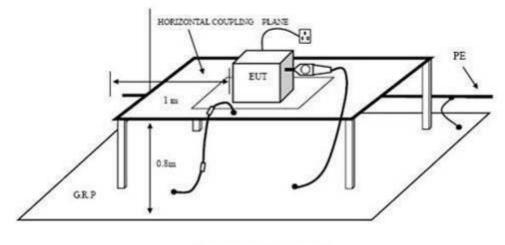
Temporary loss of function is allowed, provided the function is self-recoverable or can be restored by the operation of the controls.



12.ELECTROSTATIC DISCHARGE IMMUNITY TEST

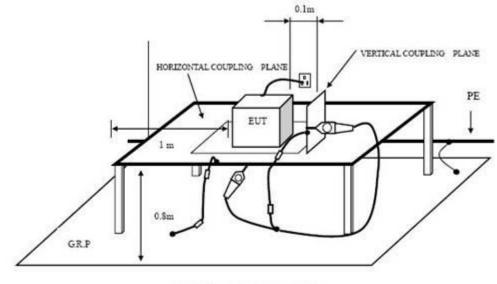
12.1.Configuration of Test System

12.1.1. Configuration of ESD Test System(Direct Discharge)



DIRECT DISCHARGE SETUP

12.1.2.Configuration of ESD Test System(Indirect Discharge)



INDIRECT DISCHARGE SETUP

12.2.Test Standard

EN 61000-6-1:2007 (IEC 61000-4-2:2008) (Severity Level 3 for Air Discharge at 8KV, Severity Level 2 for Contact Discharge at 4KV)



12.3. Severity Levels and Performance Criterion

12.3.1.Severity level

Level	Test Voltage	Test Voltage
	Contact Discharge (KV)	Air Discharge (KV)
1.	2	2
2.	4	4
3.	6	8
4.	8	15
X	Special	Special

12.3.2.Performance criterion : **B**

12.4.Test Procedure

12.4.1.Air Discharge:

The test was applied on non-conductive surfaces of EUT. The round discharge tip of the discharge electrode was approached as fast as possible to touch the EUT. After each discharge, the discharge electrode was removed from the EUT. The generator was re-triggered for a new single discharge and repeated 20 times for each pre-selected test point. This procedure was repeated until all the air discharge completed

12.4.2.Contact Discharge:

All the procedure was same as Section 12.4.1. except that the generator was re-triggered for a new single discharge and repeated 50 times for each pre-selected test point. the tip of the discharge electrode was touch the EUT before the discharge switch was operated.

12.5.Test Results

- 12.5.1.Test Results: PASS
- 12.5.2.Test data on the following pages.



Electrostatic Discharge Test Results

Shenzhen Most Technology Service Co., Ltd.

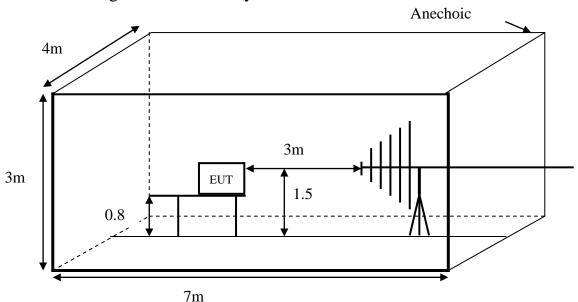
Test Voltage :	1		Test Date:		Jan.31,	2018
Test Mode :	1		Criterion	:	В	
Temperature:	25 C		Humidity:		55%	
Air Discharge: 🛨	8KV	# For Air Discha	rge each Point	Positive 10	times and	negative 10
		times discharg	e.			
Contact Discharg	ge: ±4KV	# For Contact D	ischarge each	point positiv	ve 10 time	s and
		negative 10 tin	nes discharge			
		Test Result.	s Description	-		
	La	ocation		Kina A-Air Disc C-Cont Discha	charge tact	Result
Switch				A		PASS
Ports				С		PASS
Gaps				A		PASS
НСР				С		PASS
VCP of Front				С		PASS
VCP of Rear				С		PASS
VCP of Left				С		PASS
VCP of Right				С		PASS
Remark :						

Discharge was considered on Contact and Air and Horizontal Coupling Plane (HCP) and Vertical Coupling Plane (VCP).

Reviewer : _____



13.RF FIELD STRENGTH SUSCEPTIBILITY TEST



13.1.Configuration of Test System

13.2.Test Standard

EN 61000-6-1:2007 (IEC 61000-4-3:2006+A1:2007+A2:2010) (Severity Level: 2 at 3V / m, 1 at 1V/m)

13.3. Severity Levels and Performance Criterion

Level	Test Field Strength V/m		
1.	1		
2.	3		
3.	10		
X	K Special		

13.3.2.Performance criterion : A



13.4.Test Procedure

Testing was performed in a Fully anechoic chamber as recommended by IEC 61000-4-3. The EUT was placed on an 80 cm high non-conductive table located in the area of field uniformity. The radiating antenna was placed 3m in front of the EUT and Support system, and dwell time of the radiated interference was controlled by an automated,

computer-controlled system. The signal source was stepped through the applicable frequency

range at a rate no faster than 1% of the fundamental. The signal was amplitude modulated

80% over the frequency range 80 MHz to 1GHz and 1.4GHz to 2GHz at a level of 3 V/m,

2.0GHz to 2.7GHz at a level of 1V/m. The dwell time was set at 1.5 s. Field presence was monitored during testing via a field probe placed in close proximity to the EUT. Throughout testing, the EUT was closely monitored for signs of susceptibility. The test was performed with the antennae oriented in both a horizontal and vertical polarization.

.

All the scanning conditions are as follows :

	Condition of Test	Remarks
1.	Test Fielded Strength	3 V/m (Severity Level 2)
2.	Radiated Signal	1V/m(Severity Level 1) 80% amplitude modulated with a
	~ · -	1kHz sine wave
3.	Scanning Frequency	80 - 1000 MHz, 1.4GHz-2.7GHz
4.	Sweeping time of radiated	0.0015 decade/s
5.	Dwell Time	1.5 Sec.

13.5.Test Results

13.5.1.Test Results: PASS

13.5.2.Test data on the following pages.



RF Field Strength Susceptibility Test Results

Shenzhen Most Technology Service Co., Ltd.

Test Voltage :	1		Test Date :	Jan.31, 2018
Test Mode :	1		Criterion :	A
Field Strength :	3 V/m		Frequency Range:	80-1000MHz, 1.4GHz-2GHz
Temperature:	26 C		Humidity:	54%
Modulation:	Ø AM	\Box Pulse	□none 1 k	Hz 80%
		Test Result	ts Description	
	80MH	-	ry Rang 1: z, 1400MHz – 2000MH	Iz
Step	PS		1%	1%
		Horiz	zontal	Vertical
Front PA			ISS	PASS
Right PA			ISS	PASS
Rear PA		ISS	PASS	
Left PA		ISS	PASS	

Note: No function loss

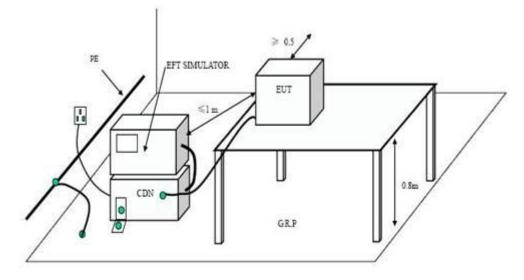
Reviewer :

Sunny



14.ELECTRICAL FAST TRANSIENT/BURST IMMUNITY TEST

14.1.Configuration of Test System



14.2.Test Standard

EN 61000-6-1:2007(IEC 61000-4-4:2012) (Severity Level 2 at 1KV)

14.3. Severity Levels and Performance Criterion

Open Circuit Output Test Voltage ±10%						
Level	On Power Supply	On I/O (Input/Output)				
	Lines	Signal data and control lines				
1.	0.5 KV	0.25 KV				
2.	1 KV	0.5 KV				
3.	2 KV	1 KV				
4.	4 KV	2 KV				
X	Special	Special				

14.3.1.Severity level

14.3.2.Performance criterion : **B**



14.4.Test Procedure

The EUT and its simulators were placed on a the ground reference plane and were insulated from it by an wood support $0.1m \pm 0.01m$ thick. The ground reference plane was 1m*1m metallic sheet with 0.65mm minimum thickness. This reference ground plane was project beyond the EUT by at least 0.1m on all sides and the minimum distance between EUT and all other conductive structure, except the ground plane was more than 0.5m. All cables to the EUT was placed on the wood support, cables not subject to EFT/B was routed as far as possible from the cable under test to minimize the coupling between the cables.

14.4.1.For input and AC power ports:

The EUT was connected to the power mains by using a coupling device which couples the EFT interference signal to AC power lines. Both positive transients and negative transients of test voltage was applied during compliance test and the duration of the test can't less than 2mins.

14.4.2.For signal lines and control lines ports:

It's unnecessary to test.

14.4.3.For DC input and DC output power ports:

It's unnecessary to test.

14.5.Test Results

- 14.5.1.Test Results: PASS
- 14.5.2.Test data on the following pages.



Electrical Fast Transient/Burst Test Results

Shenzhen Most Technology Service Co., Ltd.

Test Voltage	:	1				Test Date:		Jan.31,	2018	
Test Mode	:	1				Criterion	:	В		
Temperature.	•	25 C	r			Humidity:		55%		
				Tes	t Results De	escription		I		
Inject Line		oltage KV	Inject Time(s)	Inject Method	Results	Inject Line	Voltage KV	Inject Time(s)	Inject Method	Results
L		±1	120	Direct	PASS					
N		±1	120	Direct	PASS					
LN		±1	120	Direct	PASS					
Remark:										

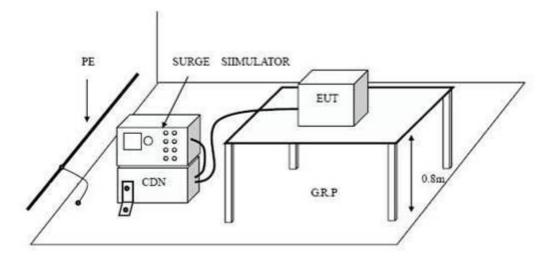
Reviewer :

Sunny



15.SURGE TEST

15.1.Configuration of Test System



15.2.Test Standard

EN 61000-6-1:2007(IEC 61000-4-5:2014) (Severity Level : Line to Line was Level 2 at 1KV Line to PE was Level 3 at 2KV)

15.3. Severity Levels and Performance Criterion

15.3.1.Severity	level
-----------------	-------

Severity Level	Open-Circuit Test Voltage			
	KV			
1	0.5			
2	1.0			
3	2.0			
4	4.0			
*	Special			

15.3.2.Performance criterion : **B**



15.4.Test Procedure

- 15.4.1.Set up the EUT and test generator as shown on Section 15.1.
- 15.4.2.For line to line coupling mode, provide a 1KV 1.2/50us voltage surge (at open-circuit condition) and 8/20us current surge to EUT selected points, and for active line / neutral line to ground are same except test level is 2KV.
- 15.4.3.At least 5 positive and 5 negative (polarity) tests with a maximum 1/min repetition rate are applied during test.
- 15.4.4.Different phase angles are done individually.
- 15.4.5.Record the EUT operating situation during compliance test and decide the EUT immunity criterion for above each test.

15.5.Test Results

- 15.5.1.Test Results: PASS
- 15.5.2.Test data on the following pages.



Surge Immunity Test Results Shenzhen Most Technology Service Co., Ltd.

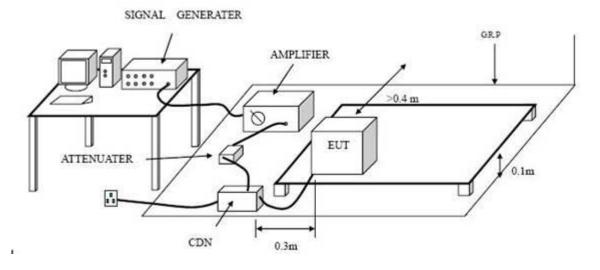
Test Voltage :	1			Test Date:	Jan.31, 2018
Test Mode :	1			Criterion	В
Temperature:	25 °C			Humidity:	55%
		Tes	t Results Descrip	otion	
Location	Polarity	Phase Angle	No of Pulse	Pulse Voltage (KV)	Result
L-N	±	0	5	1.0	PASS
	±	90	5	1.0	PASS
	±	180	5	1.0	PASS
	±	270	5	1.0	PASS
Remark:					
itemuitt.					

Reviewer : Summy



16. INJECTED CURRENTS SUSCEPTIBILITY TEST

16.1.Configuration of Test System



16.2.Test Standard

EN 61000-6-1:2007(IEC 61000-4-6:2013) (Severity Level 2 at 3V (r.m.s.) and frequency is from 0.15MHz to 80MHz)

16.3. Severity Levels and Performance Criterion

16.3.1.Severity level

Level	Voltage Level (e.m.f.) V
1.	1
2.	3
3.	10
X	Special

16.3.2.Performance criterion: A



16.4.Test Procedure

- 16.4.1.Set up the EUT, CDN and test generators as shown on Section 16.1.
- 16.4.2.Let the EUT work in test mode and test it.
- 16.4.3. The EUT are placed on an insulating support 0.1m high above a ground reference plane. CDN (coupling and decoupling device) is placed on the ground plane about 0.3m from EUT. Cables between CDN and EUT are as short as possible, and their height above the ground reference plane shall be between 30 and 50 mm (where possible).
- 16.4.4. The disturbance signal description below is injected to EUT through CDN.
- 16.4.5. The EUT operates within its operational mode(s) under intended climatic conditions after power on.
- 16.4.6.The frequency range is swept from 0.150MHz to 80MHz using 3V signal level, and with the disturbance signal 80% amplitude modulated with a 1KHz sine wave.
- 16.4.7. The rate of sweep shall not exceed 1.5*10-3decades/s. Where the frequency is swept incrementally, the step size shall not exceed 1% of the start and thereafter 1% of the preceding frequency value.
- 16.4.8.Recording the EUT operating situation during compliance testing and decide the EUT immunity criterion.

16.5.Test Results

- 16.5.1.Test Results: PASS
- 16.5.2.Test data on the following pages.



Injected Currents Susceptibility Test Results Shenzhen Most Technology Service Co., Ltd.

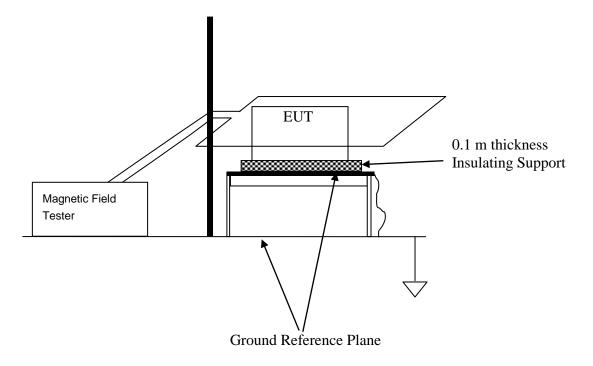
Test Mode : 1	1		Test Date:		Jan.31, 2018	
	1		Criterion :		Α	
Temperature: 2	26 °C		Humidity:		55%	
· · · ·	Test	t Results D	escription			
Frequency Range (MHz)	Intected Position		ige Level e.m.f.)	Criteri	on	Result
0.15 ~ 80	ΔI Mains		⁷ (rms), odulated	Α		PASS

Reviewer : _____



17.MAGNETIC FIELD IMMUNITY TEST

17.1.Configuration of Test System



17.2.Test Standard

EN 61000-6-1:2007 (IEC 61000-4-8:2009) (Severity Level 2 at 3A/m)

17.3. Severity Levels and Performance Criterion

17.3.1.Severity level

Level	Magnetic Field Strength A/m
1.	1
2.	3
3.	10
4.	30
5.	100
X.	Special

17.3.2.Performance criterion : A



17.4.Test Procedure

The EUT was subjected to the test magnetic field by using the induction coil of standard dimensions (1m*1m) and shown in Section 17.1. The induction coil was then rotated by 90° in order to expose the EUT to the test field with different orientations.

17.5.Test Results

- 17.5.1.Test Results: PASS
- 17.5.2.Test data on the following pages.



Magnetic Field Immunity Test Results

Shenzhen Most Technology Service Co., Ltd.

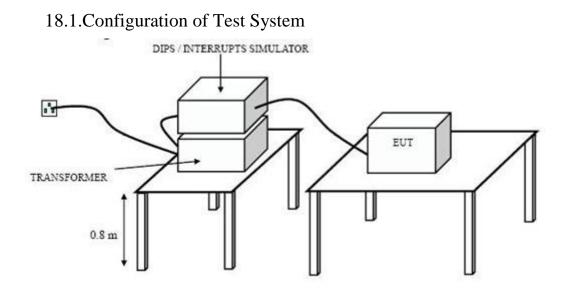
Test Voltage :	1		Test Date:	Jan.31	1, 2018			
Test Mode :	1		Criterion	Α				
Temperature:	25 °C		Humidity:	56%				
Test Results Description								
Test Level	Testing Duration	Coil Orientation	Criterio	on	Result			
3A/m(50Hz/60Hz)	5 mins	X	Α		PASS			
3A/m(50Hz/60Hz)	5 mins	Y	Α		PASS			
3A/m(50Hz/60Hz)	5 mins	Ζ	A		PASS			

Remark: No function loss

Summy Reviewer :



18.VOLTAGE DIPS AND INTERRUPTIONS TEST



18.2.Test Standard

EN 61000-6-1:2007(IE	C 61000-4-11:2004)
(Severity level: 0%	250/300 periods
0%	1.0/0.5 periods
70%	25/30 periods)

18.3. Severity Levels and Performance Criterion

18.3.1.Severity level

Test Level	Voltage dip and	Performance	Duration
%Uт	short interruptions	Criterion	(in period)
	%Uт		
0	100	В	1.0/0.5
70	30	С	25(at 50Hz)
			30(at 60Hz)
0	100	С	250(at 50Hz)
			300(at 60Hz)

18.3.2. Performance criterion : **B & C**



18.4.Test Procedure

18.4.1.The EUT and test generator were setup as shown on Section 18.1.

18.4.2. The interruptions is introduced at selected phase angles with specified duration.

18.4.3.Record any degradation of performance.

18.5.Test Results

- 18.5.1.Test Results: PASS
- 18.5.2.Test data on the following pages.



Voltage Dips And Interruptions Test Results

Shenzhen Most Technology Service Co., Ltd.

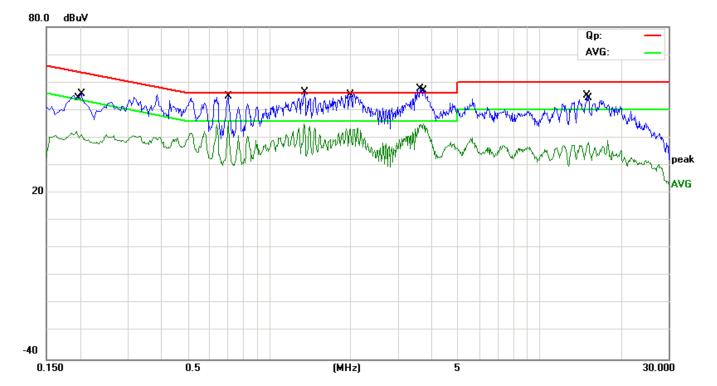
Test Voltage :	1		Test Date:	Jan.31, 2018			
Test Mode :	1		Criterion	B&C	B&C		
Temperature:	25 °C		Humidity:	55%	55%		
	1	cription					
Test Level % U _T	Voltage Dips & Short Interruptions % U _T	Duration (in period)	Phase Angle	Criterion	Result		
0	100	1P/0.5P	0 °~360 °	В	PASS		
70	30	25P(at 50Hz)	0 °~360 °	С	PASS		
		30P(at 60Hz)					
0	100	250P(at 50Hz)	0 °~360 °	С	PASS		
		300P(at 60Hz)					

Reviewer :

Sunny

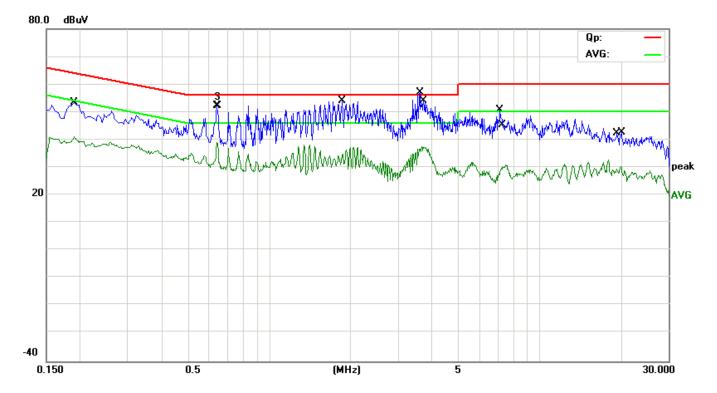
APPENDIX I

EUT:	Scooter	M/N:	ES-03
Mode:	Running	Phase:	L1
Tested by:	Joe	Power:	DC 5V by USB port
Temperature: / Humidity	25°C/ 53%	Test date:	2018-01-31



No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1		0.1940	32.74	9.60	42.34	53.86	-11.52	AVG	
2		0.2020	46.21	9.60	55.81	63.53	-7.72	QP	
3		0.7060	41.80	9.60	51.40	56.00	-4.60	QP	
4	*	0.7060	33.10	9.60	42.70	46.00	-3.30	AVG	
5		1.3500	32.10	9.60	41.70	46.00	-4.30	AVG	
6		1.3540	43.10	9.60	52.70	56.00	-3.30	QP	
7		1.9980	42.50	9.60	52.10	56.00	-3.90	QP	
8		1.9980	31.80	9.60	41.40	46.00	-4.60	AVG	
9		3.6060	41.20	9.62	50.82	56.00	-5.18	QP	
10		3.7300	32.90	9.62	42.52	46.00	-3.48	AVG	
11		15.0340	45.47	9.70	55.17	60.00	-4.83	QP	
12		15.2260	28.60	9.70	38.30	50.00	-11.70	AVG	

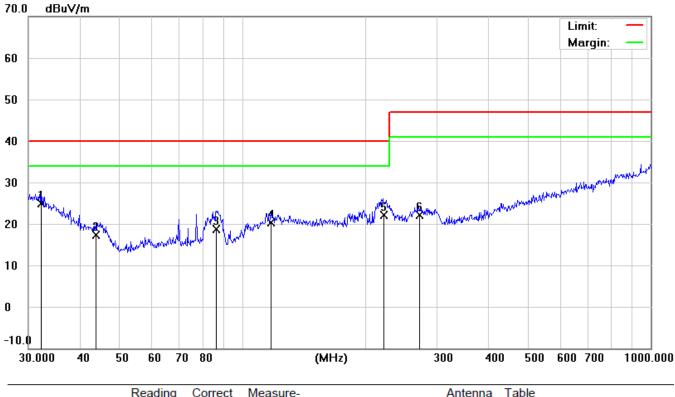
EUT:	Scooter	M/N:	ES-03
Mode:	Running	Phase:	Ν
Tested by:	Joe	Power:	DC 5V by USB port
Temperature: / Humidity	25°C/ 53%	Test date:	2018-01-31



1 0.1 2 0.1	1900 4 1900 3	dBu∨ 13.95 31.41	dB 9.60 9.60	dBu∨ 53.55	dBuV	dB	Detector	Comment
2 0.1	1900 3			53.55	04.04			
		31.41	0.60		64.04	-10.49	QP	
2 * 0.0	6420 /		3.00	41.01	54.04	-13.03	AVG	
3 0.0	0420 4	12.56	9.59	52.15	56.00	-3.85	peak	
4 0.6	6420 2	29.49	9.59	39.08	46.00	-6.92	AVG	
5 1.8	8660 3	36.20	9.60	45.80	56.00	-10.20	QP	
6 1.8	8740 2	25.29	9.60	34.89	46.00	-11.11	AVG	
7 3.6	6060 3	37.70	9.62	47.32	56.00	-8.68	QP	
8 3.6	6660 2	27.00	9.62	36.62	46.00	-9.38	AVG	
9 7.1	1660 4	11.18	9.65	50.83	60.00	-9.17	QP	
10 7.3	3380 2	20.45	9.65	30.10	50.00	-19.90	AVG	
11 19.4	4020 3	32.49	9.73	42.22	60.00	-17.78	QP	
12 19.9	9780 2	20.62	9.73	30.35	50.00	-19.65	AVG	

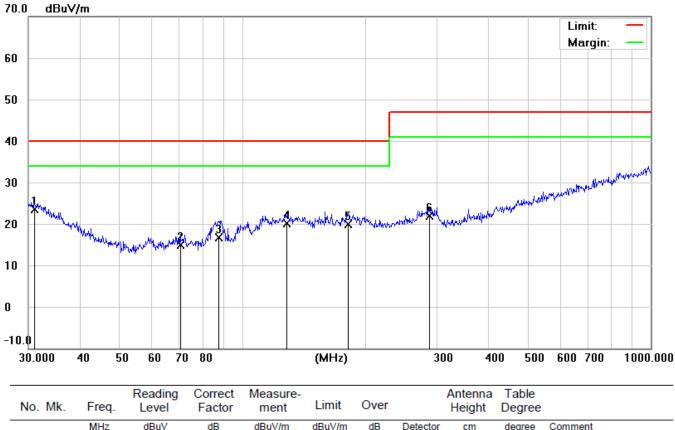
APPENDIX II

EUT:	Scooter	M/N:	ES-03
Mode:	Running	Polarizatio n	Vertical
Tested by:	Joe	Power:	DC 5V by USB port
Temperature: / Humidity	24°C/ 51%	Test date:	2018-01-31



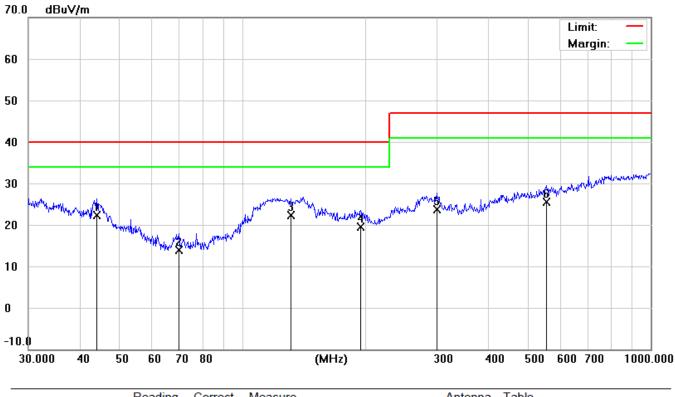
No.	Mk.	Freq.	Reading Level	Factor	Measure- ment	Limit	Over		Antenna Height	l able Degree	
		MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector	cm	degree	Comment
1	*	32.2925	3.26	21.55	24.81	40.00	-15.19	QP			
2		43.9658	3.62	13.74	17.36	40.00	-22.64	QP			
3		86.5027	7.25	11.40	18.65	40.00	-21.35	QP			
4		117.7725	3.12	17.19	20.31	40.00	-19.69	QP			
5	2	221.3921	5.69	16.33	22.02	40.00	-17.98	QP			
6	2	270.3748	3.26	18.92	22.18	47.00	-24.82	QP			

EUT:	Scooter	M/N:	ES-03
Mode:	Running	Polarizatio n	Horizontal
Tested by:	Joe	Power:	DC 5V by USB port
Temperature: / Humidity	24°C/ 51%	Test date:	2018-01-31



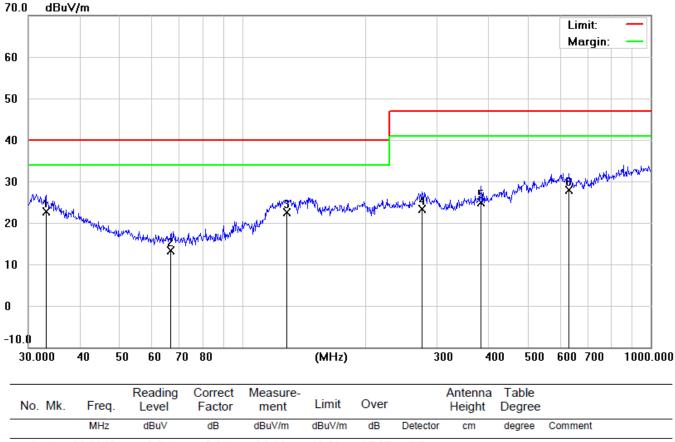
	MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector	cm	degree	Comment
1 *	31.0706	2.14	21.37	23.51	40.00	-16.49	QP			
2	70.5835	3.18	11.68	14.86	40.00	-25.14	QP			
3	87.7246	5.36	11.40	16.76	40.00	-23.24	QP			
4	128.1129	2.49	17.66	20.15	40.00	-19.85	QP			
5	181.9202	3.24	16.68	19.92	40.00	-20.08	QP			
6	287.9904	2.45	19.40	21.85	47.00	-25.15	QP			

EUT:	Scooter	M/N:	ES-03	
Mode:	Running	Polarizatio n	Vertical	
Tested by:	Joe	Power:	DC 5V by USB port	
Temperature: / Humidity	24°C/ 51%	Test date:	2018-01-31	



No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector	cm	degree	Comment
1		44.1202	8.60	13.65	22.25	40.00	-17.75	QP			
2		70.0902	2.24	11.70	13.94	40.00	-26.06	QP			
3	*	131.7574	4.70	17.61	22.31	40.00	-17.69	QP			
4		195.1363	2.42	17.01	19.43	40.00	-20.57	QP			
5		299.3158	4.37	19.31	23.68	47.00	-23.32	QP			
6		554.8254	2.89	22.60	25.49	47.00	-21.51	QP			

EUT:	Scooter	M/N:	ES-03	
Mode:	Running	Polarizatio n	Horizontal	
Tested by:	Joe	Power:	DC 5V by USB port	
Temperature: / Humidity	24°C/ 51%	Test date:	2018-01-31	



		IVIT12	ubuv	ub	ubuv/m	ubuviii	ub	Delector	CIII	uegree	Comment
1	*	33.0949	2.64	19.99	22.63	40.00	-17.37	QP			
2		66.9669	1.82	11.43	13.25	40.00	-26.75	QP			
3		128.5629	4.76	17.67	22.43	40.00	-17.57	QP			
4		275.1570	4.13	19.16	23.29	47.00	-23.71	QP			
5		383.9318	6.78	18.18	24.96	47.00	-22.04	QP			
6		631.6883	4.08	23.83	27.91	47.00	-19.09	QP			

APPENDIX III (Test Photos)

Conducted Test Setup Photograph

Radiated Test Setup Photograph



APPENDIX IV (Photos of the EUT)

Figure 1 General Appearance of the EUT



Figure 2 General Appearance of the EUT



Figure 3 General Appearance of the EUT



Figure 4 General Appearance of the EUT



Figure 5 Components side of the PCB

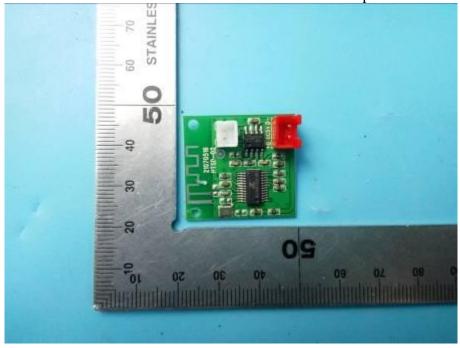


Figure 6 Components side of the PCB

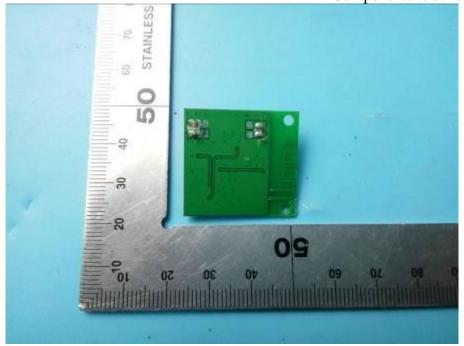


Figure 7 Components side of the PCB

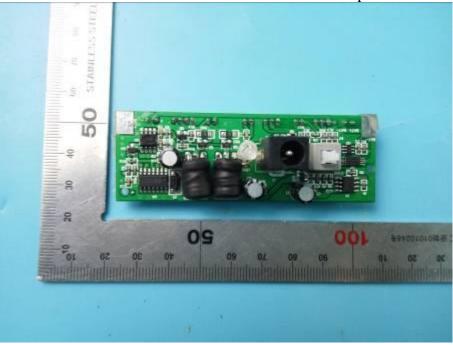


Figure 8 Components side of the PCB

